

Dr. Michael Downer

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3:15 PM

***In-situ* epi-optic characterization of electronic and structural materials**

Our lab specializes in characterizing surfaces, interfaces and nanostructures using noninvasive optical probes. I will describe recent results on a variety of epi-optic applications: monitoring of chemical bonding sites for nano-wires and organic films on vicinal silicon surfaces; optical characterization of antiphase domains in III-V films integrated onto silicon substrates; optical characterization of strain fields in 3D integrated microelectronics; optical characterization of temperature- and composition-dependent microstructure in asphalt binders.

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